

PATENT ABSTRACTS OF JAPAN

(11)Publication number : 2000-206149

(43)Date of publication of application : 28.07.2000

(51)Int.Cl.

G01R 1/073

G01R 31/26

H01L 21/66

(21)Application number : 11-007215

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(22)Date of filing : 14.01.1999

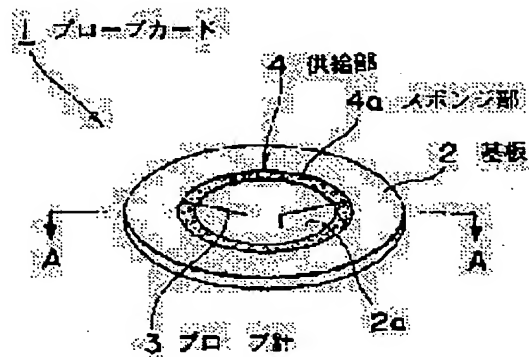
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(54) PROBE CARD AND METHOD FOR TESTING ELECTRIC CHARACTERISTIC OF BODY TO BE TESTED

(57)Abstract:

PROBLEM TO BE SOLVED: To make the electric characteristics of a body to be tested testable with high accuracy without causing any defective conditions such as the adhesion of the material of the electrode pad of a body to be tested to the tip of a probe needle, the oxidation of the tip side of the probe needle.

SOLUTION: The probe card 1 is provided with a substrate 2 and a probe needle 3 in a state supported by the substrate 2 extended downward from the probe card 1, and the tip of the probe needle 3 is brought into contact with an electrode pad of a body to be inspected to test the electric characteristics of the body to be tested. The probe card 1 is provided with a supply part 4 for supplying the probe needle 3 with a coating liquid so as to coat the surface of the tip side of the probe needle 3 at all times. The coating liquid is formed of a liquid which is non-conductive, is nonvolatile in test atmosphere, and does not corrode the body to be tested. At the time of test, by bringing the tip of the probe needle 3 into contact with the electrode pad of the body to be tested as coating the surface of the tip side of the probe needle 3 with the coating liquid, the electric characteristics of the body to be tested are tested.



LEGAL STATUS

[Date of request for examination]

[Date of sending the examiner's decision of rejection]

[Kind of final disposal of application other than the examiner's decision of rejection or application converted registration]

[Date of final disposal for application]

[Patent number]

[Date of registration]

[Number of appeal against examiner's decision of rejection]

[Date of requesting appeal against examiner's decision of rejection]

[Date of extinction of right]